

Call for Papers

Special Issue on Event Recognition

Applied Artificial Intelligence Journal

Users and organisations collect data in various structured and unstructured digital formats, but they cannot fully utilise these data to support content and resource management. It is evident that the analysis and interpretation of the available data needs to be automated, in order for large data volumes to be transformed into operational knowledge. Events are particularly important pieces of knowledge, as they represent activities of special significance both for users and organisations. Therefore, the *recognition of events* is of utmost importance. Consider, for example, the recognition of trends given user contributions in social Web 2.0 applications, the recognition of attacks on nodes of a computer network given the exchanged TCP/IP messages, the recognition of suspicious trader behaviour given the transactions in a financial market, and the recognition of various types of cardiac arrhythmia given electrocardiograms.

We invite quality submissions focusing on various aspects of event recognition, including analysis of video, audio, text and other sensor data, as well as recognition on fused data sources. While we place emphasis on theoretical contributions, we also welcome papers describing interesting applications.

Broad topics include:

- Representation languages for event recognition
- Algorithms for real-time event recognition
- Probabilistic reasoning for event recognition
- Machine learning for event recognition
- Event recognition architectures
- Benchmarks, performance evaluations, and testbeds
- Domain-specific deployments of event recognition systems
- Multimedia and social media analysis for event recognition
- Clustering, concept recognition and multi-modal/fusion techniques
- User interaction and interfaces for event navigation, browsing and management

Key Dates

December 1, 2010 - Submissions

July 10, 2011 - Final Decisions

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Info

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